| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|---|---|---|---|---|---|---|
| L1 | 3191155 | @ad<"20010322" | USPAT | OR | ON | 2004/12/12 17:30 |
| L2 | 565751 | semiconductor or IC or LSI or VLSI or ASIC or chip or wafer | USPAT | OR | ON | 2004/12/12 17:30 |
| L3 | 3737 | metrological or metrology | USPAT | OR | ON | 2004/12/12 17:30 |
| L4 | 283 | field-to-field or (field adj to adj field) | USPAT | OR | ON | 2004/12/12 17:30 |
| L5 | 1386952 | analys$ or data or measurement or error | USPAT | OR | ON | 2004/12/12 17:30 |
| L6 | 3831 | residual-error or (residual adj error) or (residu$ adj (error or data or analysis or measurement)) | USPAT | OR | ON | 2004/12/12 17:30 |
| L7 | 2 | (semiconductor or IC or LSI or VLSI or ASIC or chip or wafer) and (metrological or metrology) and (field-to-field or (field adj to adj field)) and (analys$ or data or measurement or error) | USPAT | OR | ON | 2004/12/12 17:30 |
| L8 | 2 | (semiconductor or IC or LSI or VLSI or ASIC or chip or wafer) and ((field-to-field or (field adj to adj field)) same (analys$ or data or measurement or error)) and (residual-error or (residual adj error) or (residu$ adj (error or data or analysis or measurement))) | USPAT | OR | ON | 2004/12/12 17:30 |
| L9 | 2 | (semiconductor or IC or LSI or VLSI or ASIC or chip or wafer) and (field-to-field or (field adj to adj field)) and (analys$ or data or measurement or error) and (residual-error or (residual adj error) or (residu$ adj (error or data or analysis or measurement))) | USPAT | OR | ON | 2004/12/12 17:30 |
| L10 | 476 | 703/6.ccls. | USPAT | OR | ON | 2004/12/12 17:30 |
| L11 | 845 | 430/22.ccls. | USPAT | OR | ON | 2004/12/12 17:30 |
| L12 | 187 | 382/147.ccls. | USPAT | OR | ON | 2004/12/12 17:30 |
| L13 | 1507 | 703/6.ccls. or 430/22.ccls. or 382/147.ccls. | USPAT | OR | ON | 2004/12/12 17:30 |
| L14 | 1210 | (703/6.ccls. or 430/22.ccls. or 382/147.ccls.) and @ad<"20010322" | USPAT | OR | ON | 2004/12/12 17:30 |
| L15 | 694 | ((703/6.ccls. or 430/22.ccls. or 382/147.ccls.) and @ad<"20010322") and (semiconductor or IC or LSI or VLSI or ASIC or chip or wafer) | USPAT | OR | ON | 2004/12/12 17:30 |

| L16 | 2 | (((703/6.ccls. or 430/22.ccls. or 382/147.ccls.) and @ad<"20010322") and (semiconductor or IC or LSI or VLSI or ASIC or chip or wafer)) and (field-to-field or (field adj to adj field)) | USPAT | OR | ON | 2004/12/12 17:30 |
| L17 | 93 | wafer-mean or (wafer adj mean) | US-PGPUB; USPAT | OR | OFF | 2004/12/12 17:31 |
| L18 | 0 | 17 near2 error | US-PGPUB; USPAT | OR | ON | 2004/12/12 17:31 |
| L19 | 1 | 17 and 6 | US-PGPUB; USPAT | OR | ON | 2004/12/12 17:32 |